

Notice of References Cited	Application/Control No. 10/677,418	Applicant(s)/Patent Under Reexamination LEI ET AL.	
	Examiner Tauqir Hussain	Art Unit 2152	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0193967	10-2003	Fenton et al.	370/490
*	B	US-2002/0145984	10-2002	Babu et al.	370/312
*	C	US-2005/0256937	11-2005	Lewis, Brad	709/217
*	D	US-2004/0249768	12-2004	Kontio et al.	705/065
*	E	US-2004/0063449	04-2004	Fostick, Gideon	455/517
*	F	US-2003/0046222	03-2003	Bard et al.	705/38
*	G	US-2003/0085275	05-2003	Barkan, Edward	235/383
*	H	US-2007/0064887	03-2007	Bjorklund et al.	379/088.17
*	I	US-2005/0020250	01-2005	Chaddha et al.	455/414.1
*	J	US-2007/0076857	04-2007	Chava et al.	379/088.17
*	K	US-5,751,791	05-1998	Chen et al.	379/88.13
*	L	US-6,415,263	07-2002	Doss, Gary L.	705/26
*	M	US-2,004	03-1841	Name not available	440/90

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/677,418

Applicant(s)/Patent Under
Reexamination
LEI ET AL.

Examiner

Tauqir Hussain

Art Unit

2152

Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0038892	02-2005	Huang et al.	709/227
*	B	US-6,356,893	03-2002	Itakura et al.	707/3
*	C	US-2005/0060363	03-2005	Jang et al.	709/200
*	D	US-2007/0047523	03-2007	Jiang, John Yue Jun	370/352
*	E	US-2004/0067769	04-2004	King et al.	455/556.1
*	F	US-2004/0098625	05-2004	Lagadec et al.	713/201
*	G	US-2003/0045311	03-2003	Larikka et al.	455/466
*	H	US-6,763,226	07-2004	McZeal, Jr., Alfred	455/90.2
*	I	US-2004/0117255	06-2004	Nemirofsky et al.	705/014
*	J	US-2004/0258063	12-2004	Raith et al.	370/389
*	K	US-6,067,529	05-2000	Ray et al.	705/26
*	L	US-2004/0243719	12-2004	Roselinsky, Milt	709/245
*	M	US-2005/0259604	11-2005	Salmi, Matti	370/310

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/677,418	Applicant(s)/Patent Under Reexamination LEI ET AL.	
	Examiner Tauqir Hussain	Art Unit 2152	Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2007/0099703	05-2007	Terebilo, Yakir	463/042
*	B	US-2004/0010602	01-2004	Van Vleck et al.	709/229
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.